



# American International University- Bangladesh

## Department of Electrical and Electronic Engineering

EEE 2104: Electronic Devices Lab

### Lab Report

Semester: Fall 2022-2023

Section: T

Experiment Number: 6

Title: Study of BJT Biasing Circuit.

Submitted to-

Mohammad Zohurul Islam  
Senior Lecturer, Dept. of EEE  
Faculty of Engineering

Submitted by-

Name: Nokibul Arfin Siam  
ID: 21-44793-1

Group number: 1

Group members-

Sl.	Name	ID
1	Nokibul Arfin Siam	21-44793-1
2	Saad Bin Sami	21-45246-2
3	MD. Mehedi Hasan Ratul	21-45007-2
4	Zilani Khan	21-45785-3
5	Tamal Krishna Saha	21-45906-3

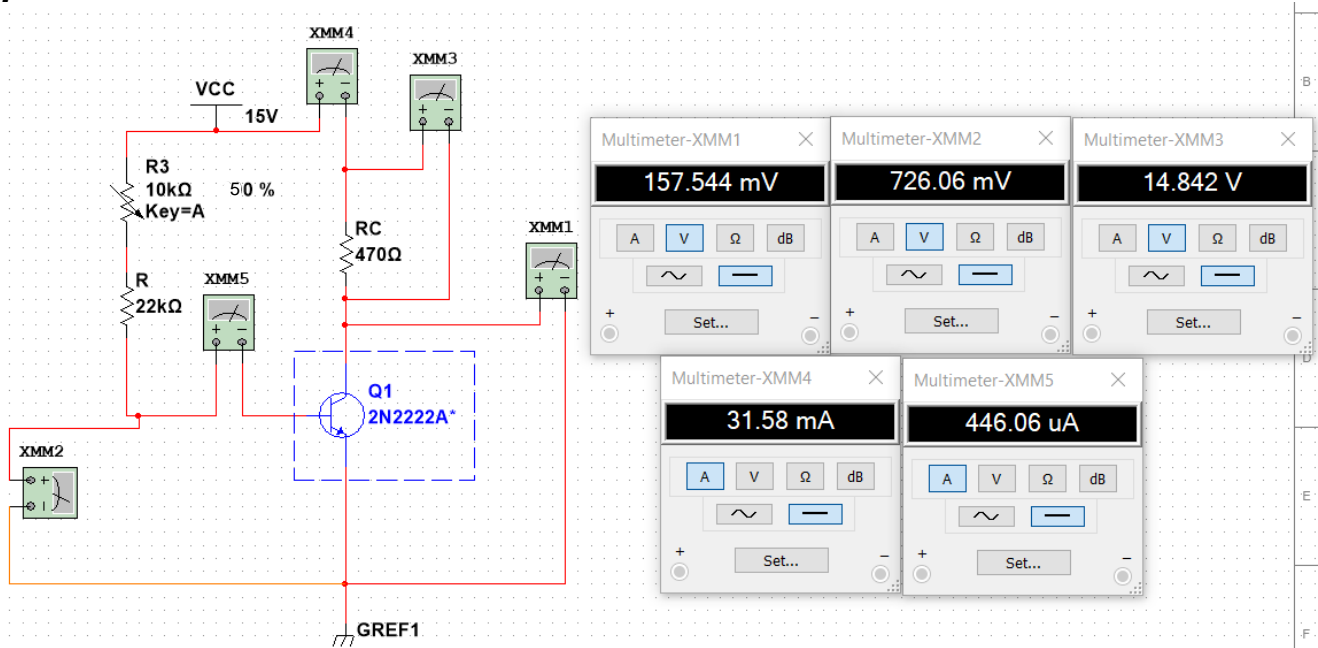
Submitted on: Click or tap to enter a date.

# **TABLE OF CONTENTS**

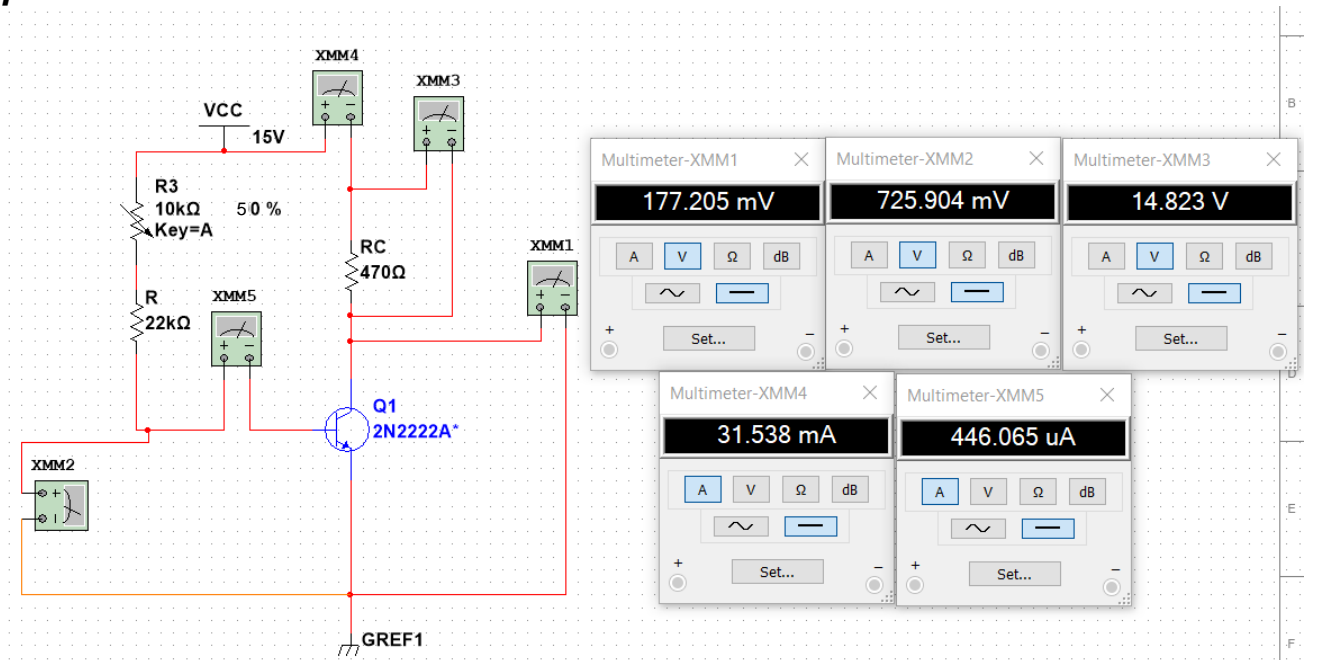
1. Abstract
2. Introduction
3. Theory and Methodology
4. Apparatus
5. Circuit Diagram
6. Simulation and Measurement
7. Experimental Data
8. Result Analysis
9. Discussion
10. Conclusion
11. Reference

## For Figure-1

$$\beta = 113$$

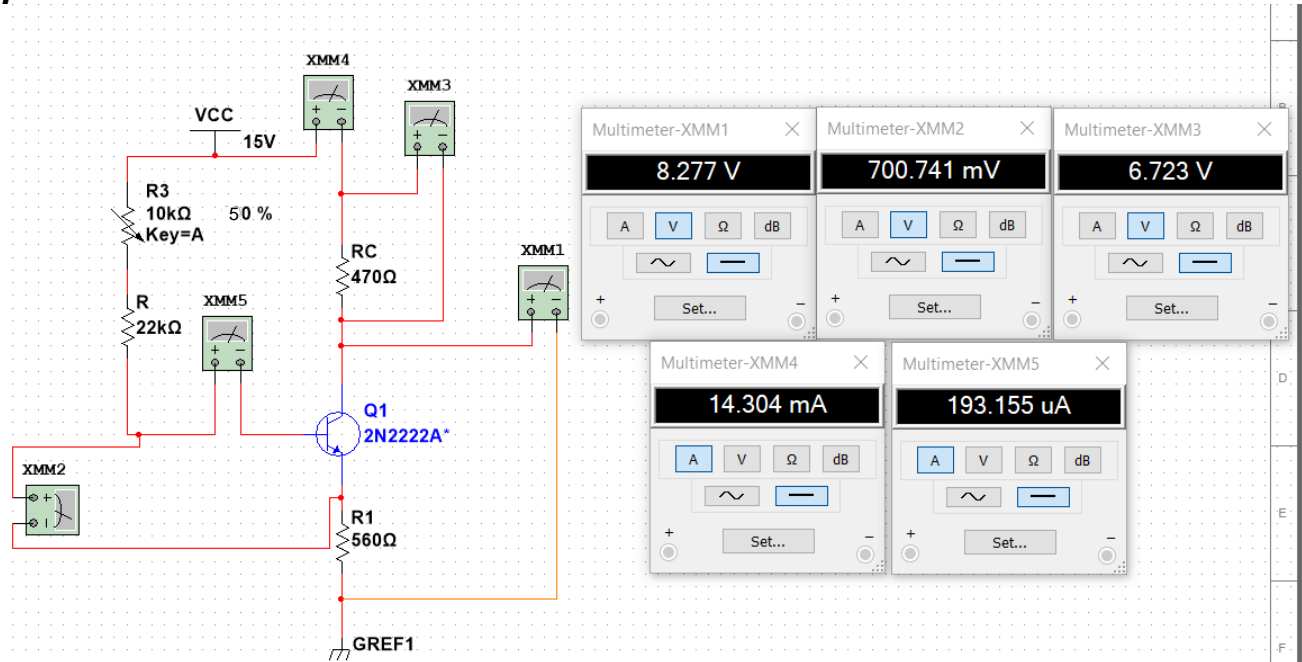


$$\beta = 94$$

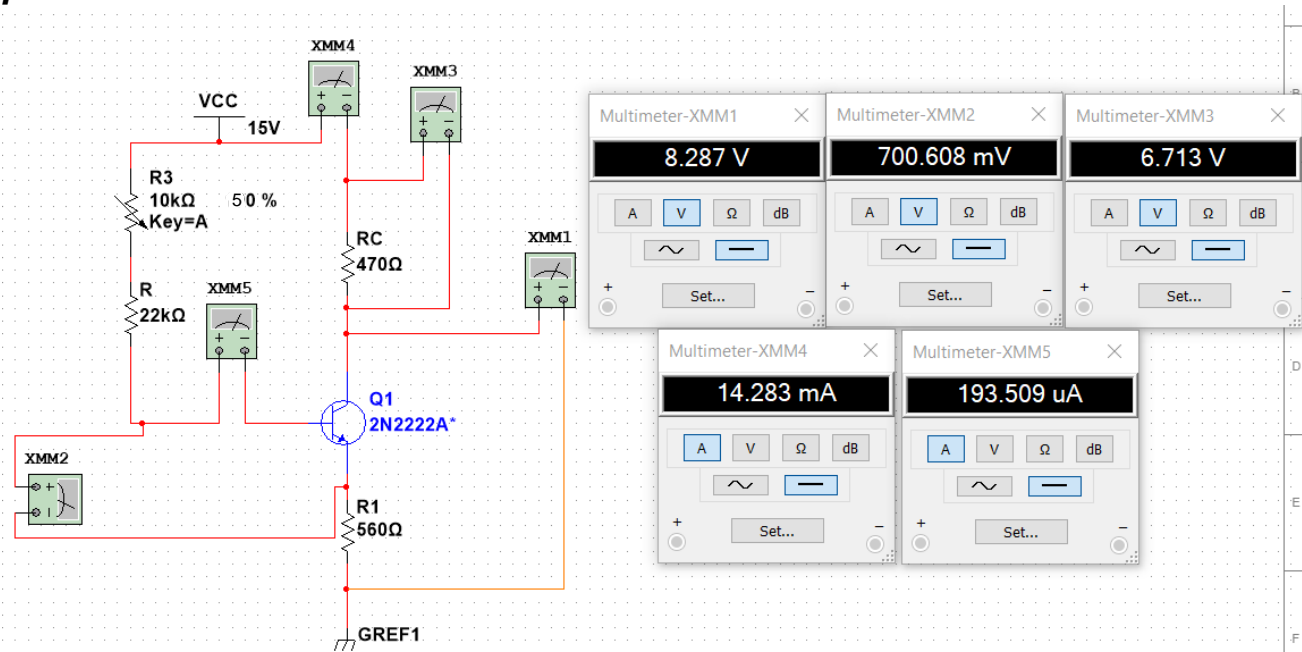


## For Figure-2

$$\beta = 113$$

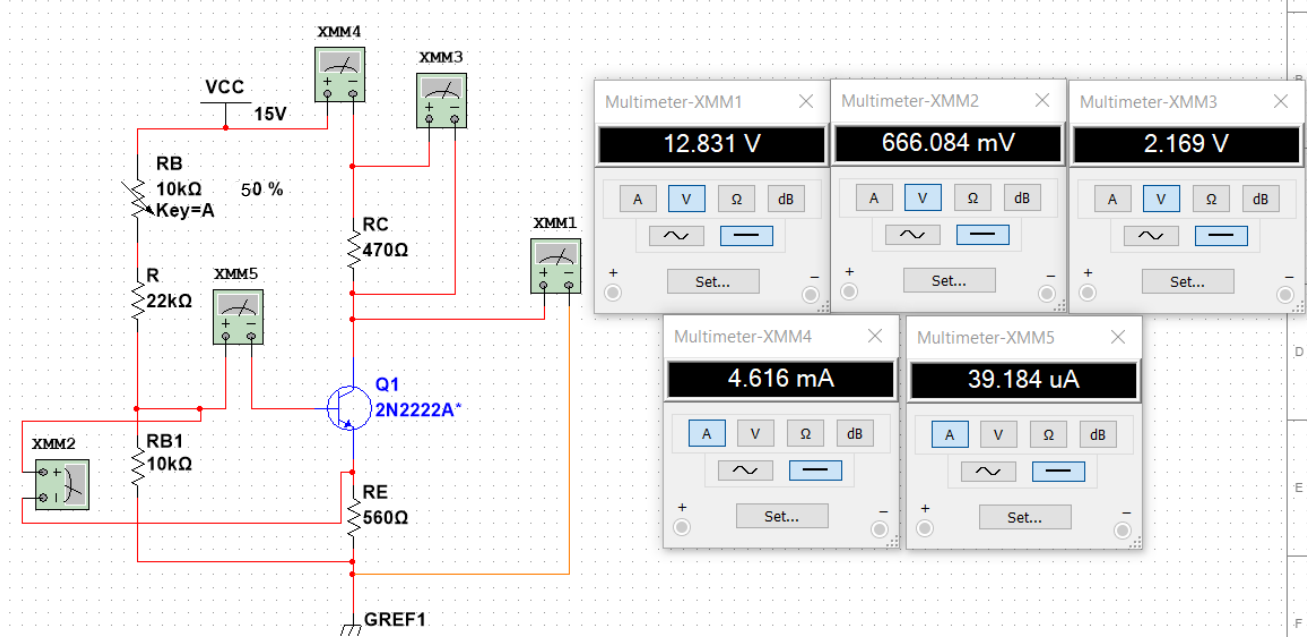


$$\beta = 94$$



## For Figure-1

$$\beta = 113$$



$$\beta = 94$$

